

A Computer Program  
for the Quantitative Interpretation of  
Mass Spectrographic Photoplates

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PAUL P. EK AND JAMES G. ALLARD

Optical Materials Branch  
Optical Physics Division

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NAVAL RESEARCH LABORATORY  
Washington, D.C.

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## **ABSTRACT**

To determine impurity concentrations in solids using mass spectrographs, ion-sensitive emulsions are used. The principal problem in obtaining quantitative results from a mass spectrum recorded on a photographic plate is determining the characteristic response curve. Calculations required to determine the parameters in an empirical function which accurately represents the response curve of Ilford Q2 emulsions are programmed in FORTRAN language. The program input data consists of the impurity-ion mass, line density, and exposure; the impurity-ion concentration and the detection limit are calculated and printed as output.

## **PROBLEM STATUS**

This is a final report on the computer program for determining impurity concentrations in solids.

## **AUTHORIZATION**

NRL Problem P03-07A  
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## A COMPUTER PROGRAM FOR THE QUANTITATIVE INTERPRETATION OF MASS SPECTROGRAPHIC PHOTOPLATES

### INTRODUCTION

Solid-state mass spectographs normally use ion-sensitive photographic plates as the output detector, due to the wide variation in ion intensity of the rf vacuum spark source. In addition, the photoplate is an excellent ion integrator and has the ability to detect and to record a wide range of masses simultaneously.

There are two principal procedures used for the analytical interpretation of photographic plates: (a) visual inspection (1), where an experienced analyst visually compares line densities and calculates concentrations from relative exposures, and (b) the photometric method (1-3), where a microdensitometer is used to determine line densities and the data are processed by manual calculations. The first method produces semiquantitative results; the latter method, by eliminating errors arising from visually matching densities, line width, emulsion background, etc., can produce quantitative results.

This report is not intended to argue in favor of one method over the other. Both methods are useful. However, if the densitometric method is used, the manual labor required to process the data is so great that the routine computation can be done best by a digital computer.

The primary problem in obtaining a quantitative analysis of a mass spectrum recorded on a photoplate is determining the characteristic response curve of the emulsion. There are several "functionless" methods (4) for obtaining the characteristic response curve, but the method most widely associated with mass spectrography is the modification by Duke (2), based on the "two-line technique" described by Churchill (5) for use in optical spectrography. The characteristic response curve may also be obtained by a "functional" method. An empirical function given by Huli (6) accurately represents the entire response range of Ilford Q2 emulsions, thus permitting all analytical data to be evaluated.

Both the functionless and the functional method have individual merit. The Churchill two-line method is applicable only for elements possessing an appropriate isotopic distribution, and it requires many pairs of measurements of two lines having a known intensity ratio (such as isotopes whose abundance ratio falls within the requisite range). In addition, only information from a single element is used to construct the characteristic curve, but Owens and Giardino (7) have demonstrated that emulsion response exhibits ion-mass dependence, ion-energy dependence, and, possibly, chemical dependence. However, Keunicott (8) has described a computer program using this method.

The functional method, in which the data are fitted to an empirical curve, is easier to program. However, it tends to force the data into a predetermined formula, and any errors of the ion-beam integrator are not corrected. Woolston (9) has described a computer program written in assembly-system language, using the functional method.

The program described below is modeled after Woolston's program, but it is written in FORTRAN IV, because NRL's CDC 3800 computer is more receptive to FORTRAN language. Generally the mathematical functions and symbols of both Woolston's program and our program are the same; there are slight additions or deletions that suited our

personal approach. However, the parameters calculated from the same data are essentially the same.

## MATHEMATICAL FORMULATION

The equation for the photographic calibration curve given by Hull (6) may be expressed by

$$K_x a_{x,i} E_x = \left( \frac{100 - T_L}{T_L - T_{SAT}} \right)_{x,i}^{1/R_x}, \quad (1)$$

where, for a sample component  $x$ ,

- $K_x$  is directly proportional to the component concentration in the total ion beam striking the plate and to the photoplate sensitivity,
- $a_{x,i}$  is the abundance of isotope  $i$  of the sample component,
- $E_x$  is the exposure, indicated by the beam-monitor integrator, in nanocoulombs,
- $T_L$  is the percent line transmission (corrected for background) of the spectral line  $i$ ,
- $T_{SAT}$  is the percent transmission of the spectral line  $i$  for an infinite (saturation) exposure, and
- $R_x$  is proportional to the maximum slope of the photographic response curve.

The corrected line transmission  $T_L$  in Eq. (1) is given by

$$T_L = \frac{100 + T_{SAT} \left[ \left( \frac{100 - T_{LB}}{T_{LB} - T_{SAT}} \right)^{1/R} - \left( \frac{100 - T_B}{T_B - T_{SAT}} \right)^{1/R} \right]^R}{1 + \left[ \left( \frac{100 - T_{LB}}{T_{LB} - T_{SAT}} \right)^{1/R} - \left( \frac{100 - T_B}{T_B - T_{SAT}} \right)^{1/R} \right]^R}, \quad (2)$$

where  $T_{LB}$  is the measured line transmission and  $T_B$  is the measured background transmission, both in percent transmission.

The sensitivity of the emulsion is proportional to  $M^{0.6}$ , where  $M$  is the mass of the ion. When this factor is included the equation for calculating the impurity-ion concentration  $C_i$  in ppma is determined from Eq. (1) and becomes

$$C_i = \frac{10^6 (MF_x)^{0.6} S_r K_x C_r}{(MF_r)^{0.6} S_x K_r}, \quad (3)$$

where  $MF$  is a factor proportional to the mass in atomic mass units,  $C_r$  is the fractional concentration of the reference ion, and  $S$  is the relative sensitivity coefficient (unless both  $S_x$  and  $S_r$  are known, they are taken to be unity).

When the lines have finite width the concentrations are corrected by a factor equal to the line width. Thus, Eq. (3) must be multiplied by  $w_{x,i} w_{r,j}$ , where  $w$  is the width of

the line as determined at the points of half-maximum on the intensity profile. When the background is considered, these points correspond to the transmission

$$T_{Lw} = \frac{100 + T_{SAT} \left[ \frac{1}{2} \left( \frac{100 - T_{LB}}{T_{LB} - T_{SAT}} \right)^{1/R_x} + \frac{1}{2} \left( \frac{100 - T_B}{T_B - T_{SAT}} \right)^{1/R_x} \right]^{R_x}}{1 + \left[ \frac{1}{2} \left( \frac{100 - T_{LB}}{T_{LB} - T_{SAT}} \right)^{1/R_x} + \frac{1}{2} \left( \frac{100 - T_B}{T_B - T_{SAT}} \right)^{1/R_x} \right]^{R_x}}. \quad (4)$$

## NUMERICAL CALCULATIONS

When only one data point is available,  $R_x$  is taken to be 1. For two data points (1 and 2)  $R_x$  is determined from the relationship

$$R_x = \frac{\log \left[ \left( \frac{100 - T_{L1}}{T_{L1} - T_{SAT}} \right) \left( \frac{T_{L2} - T_{SAT}}{100 - T_{L2}} \right) \right]}{\log \left( \frac{a_1 E_1}{a_2 E_2} \right)}, \quad (5)$$

which may be derived from Eq. (1). Only three data points are allowed in the program. When three points are used, an average value of  $R_x$  (equal to the root-mean-square of  $R_x$  obtained from the calculation for the three combinations of pairs of data points) is calculated and is designated as  $R_{AV}$ . If  $R_x$  is either greater than 1.25 or less than 1,  $R_{AV}$  is set equal to 1.0. Upon substituting  $R_{AV}$  into Eq. (1), numerical values of  $K_x$  are calculated for each data point, and the root mean square of this result, denoted by  $K_{AV}$ , is substituted into Eq. (3) to determine the ion concentration.

Numerical values of  $T_{Lw}$  are calculated from Eq. (4) for each data point; an average value of the correction for line width can be determined by the densitometric measurements, and the factor  $w_{r,i}/v_{r,i}$  can be applied to Eq. (3).

The detection limit is determined by using  $R_{AV}$  to calculate  $K_x$  for the maximum component exposure, setting  $T_L = 100\%$  and  $T_B = 98\%$  in Eq. (1) and substituting these values of  $K_x$  in Eq. (3).

## GENERAL DESCRIPTION OF THE PROGRAM

Expressions are programmed for the calculations described in the previous section for experimental data read in from punched cards. Tables of isotope abundances and identifications are punched on IBM cards and are read in preceding the experimental data cards. If an incorrect isotope identification is made on the corresponding data card, NO ISOTOPE LISTED is printed, and the calculation for that isotope is bypassed. Other errors are determined by the system error identifiers. Formats of the experimental data cards are given in Table 1.

The input data are punched on cards. A table of isotope abundances is read in with the measured data. Table 2 gives a definition of the symbols used in the program.

Cards 3 through 4 + (N - 1) are included, in order, for each isotope. Three cards (identified as 23-1, 23-2, and 23-3) may be inserted into the program between cards 23 and 24. The data are then punched in as optical density.

Table 1  
Input Data Format

Data Card Number	Format	Symbols
1	(55H )	Run Identification
2	(1x, <u>I4</u> , 10x, <u>E11.4</u> , 2x, <u>F10.4</u> )	NO RUNS, REF CONC, EIM X
3	(1x, <u>F4.1</u> , 9x, <u>F7.2</u> , 10x, <u>I2</u> , 10x, <u>A8</u> , A1, 7x, <u>F5.2</u> )	CHG, ATWT, N, Q, S*
4 through 4 + (N - 1)	( <u>A8</u> 1x, <u>F8.4</u> , 2 (2x, <u>F8.4</u> ), 3x, <u>E10.3</u> )	ID, TLB, TB, TSAT, EI

\*The sequence of cards 3 through 4 + (N - 1) is repeated a number of times equal to the number of runs.

Table 2  
Definition of Symbols

Card Number	Symbol	Definition
2	NO RUNS	The number of isotopes processed
2	Ref Conc	The concentration of the reference isotope
2	EIMAX	The maximum photoplate exposure in nanocoulombs
3	CHG	The isotopic charge
3	ATWT	The average atomic weight of the element
3	N	The number of data points used for the isotope processed
3	Q	The comments
3	S	(Defined in text)
4	ID	The atomic symbol and mass number
4	TLB, TB, TSAT, EI	(Defined in text)

The first 1-2 characters in the A8 specification of ID refers to the atomic symbol, and the last 1-3 characters correspond to the atomic mass.

#### ACKNOWLEDGMENT

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## Appendix A

### PROGRAM LISTING

```

PROGRAM SPECTRA          1
DIMENSION TLB(3),TB(3),TSAT(3),TLW(3),TL(3),R(3),KX(3),ID2(3),  2
CID(3),AB(287),IDEN(287),MASS(287),MI(3),EI(3),AI(3),Q(2)      3
TYPE REAL MFACTOR,KAV,KX,MI,KDL,KAVR                           4
201 FORMAT(7F10.5)        5
202 FORMAT(9A8)          6
203 FORMAT(19I4)         7
204 FORMAT(2(0I6))       8
READ201,AB              9
READ202,IDEN            10
READ203,MASS            11
READ204,MSK1,MSK2       12
LINES=47                13
READ 206                14
PRINT 205               15
PPINT 206               16
CALL HEADING             17
RFAD30 ,NO RUNS,REF CONC,EIMAX           18
DO 26 I=1,NO RUNS        19
READ 31,CHG,AT WT,N,Q,S           20
MFACTOR=(AT WT/(30.0*CHG))*C.6      21
DO 4 J=1,N               22
READ 32,IDL(J),TLB(J),TB(J),TSAT(J),EI(J)           23
TLB(J)=10.0**(-TLB(J))*100.0          23-1
TB(J)=10.0**(-TB(J))*100.0          23-2
TSAT(J)=10.0**(-TSAT(J))*100.0      23-3
ID2(J)=MSK2.AND.ID(J)             24
L=0                         25
1 L=L+1                  26
IF(L.GT.287)33,2             27
2 IF(ID(J).EQ.IDEN(L))3,1      28
3 AI(J)=AB(L)/100.0          29
MI(J)=MASS(L)                30
CALL CALC TL(TLB(J),TB(J),TSAT(J),TL(J))           31
4 CONTINUE                 32
ID1=MSK1.AND.ID             33
IF(N.EQ.1)5,6                34
5 R=1.0                     35
R(2)=1.0                   36
RAV=1.0                     37
CALL CALC K(R,TL,TSAT,EI,AI,KX)           38
CALL CALC TLW(R,TLB,TB,TSAT,TLW)           39
KAV=MFACTOR*KX              40
GO TO 11                    41
6 IF(N.EQ.2)7,9              42
7 CALL CALC R(TL,TL(2),AI*EI,AI(2)*EI(2),TSAT,TSAT(2),R)    43
R(2)=R                      44
RAV=R                      45
DO 8 M=1,2                  46
CALL CALC K(R,TL(M),TSAT(M),EI(M),AI(M),KX(M))           47
8 CALL CALC TLW(R,TLB(M),TB(M),TSAT(M),TLW(M))           48
KAV= SQRT(KX*KX(2))*MFACTOR           49
GO TO 11                    50
9 DO 10 M=2,3              51

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10 CALL CALC R(TL,TL(M),AI*EI,AI(N)*EI(M),TSAT,TSAT(M),R(M-1))      52
    CALL CALC R(TL(2),TL(3),AI(2)*EI(2),AI(3)*EI(3),TSAT(2),TSAT(3),      53
    CR(3))
    EX=1.0/3.0
    RAV=(R*RI(2)*R(3))**EX
    DO101 M=1,3
    CALL CALC K(RAV,TL(M),ISAT(M),EI(M),AI(M),KX(M))                  58
101 CALL CALC TLW(RAV,TLB(M),TL(M),TSAT(M),TLW(M))                   59
    KAV=(KX*KX(2)*KX(3))**EX*MFACTUR
    IF(I.EQ.1)12,13
    11 CI=RFF CONC
    12 CI=REF CONC
    SR=S
    KAVR=KAV
    GO TO 131
    13 CI= SR*KAV/(S*KAVR)* REF CONC
131 IF(N.EQ.1)14,15
    14 M1=1
    GO TO 20
    15 N1=N-1
    DO 18 M=1,N1
    IF(AI(M).LT.AI(M+1))16,17
    16 M1=M+1
    GO TO 18
    17 M1=M
    18 CONTINUE
    IF(N.EQ.3)19,20
    19 RX=RAV
    GO TO 21
    20 RX=R
    21 CALL CALC K(RX,98.0,0.0,EIMAX,AI(M1),KDL)
    DET LIM=SR*KDL/(KAVR*S)* REF CONC*MFACTUR
    PRINT 27,D1,C1,DET LIM,Q(1),Q(2),ID2(1),TLB(1),TB(1),ISAT(1),
    CTL(1),TLW(1),R(1),KX(1),MFACTUR,S,EI(1)
    IF(N.EQ.1)24,23
    23 DO 231 LN=2,N
    PRINT 28, ID2(LN),TLB(LN),TB(LN),TSAT(LN),TL(LN),TLW(LN),R(LN),
    CXX(LN),EI(LN)
231 CONTINUE
    24 PRINT 29,RAV,KAV
    LINES=LINES-N-3
    IF(LINES.LT.0)25,26
    25 LINES=47
    PR,NT 205
    PRINT 26
    CALL HEADING
    26 CONTINUE
    GO TO 35
    33 PRINT 34
    34 FORMAT(19H ISOTOPE NOT LISTED)
    IF(I.EQ.NO RIJNS)35,36
    27 FORMAT(3X,A2,4X,E10.3,2X,F8.4,3X,A9,A1,2X,R3,5(2X,F5.1),5X,F6.3,
    C6X,E10.3,2X,F6.3,2X,F5.2,2X,E8.1)                                102
    28 FORMAT(43X,R3,5(2X,F5.1),5X,F6.3,6X,E10.3,17X,E8.1)          104
    29 FORMAT(82X,4HRAV=,F5.3,2X,4HKAV=,E10.3,/)                      105
205 FORMAT(1H1)                                                       106
206 FORMAT(95H)                                                       107
    30 FORMAT(1X,14,10X,E11.4,2X,F10.4)                                 108
    31 FORMAT(1X,F4.1,9X,F7.2,1CX,I2,10X,A8,A1,7X,F5.2)           109
    32 FOPMAT(A8,1X,F8.4,2(2X,F8.4),3X,E10.3)                         110
    36 IF(J.EQ.N)26,37
    37 JE1=J+1
    DO 38 JE=JE1,N
    READ 32, ID(JE),TLB(JE),TB(JE),ISAT(JE),EI(JE)                     113
    READ 32, ID(JE),TLB(JE),TB(JE),ISAT(JE),EI(JE)                     114

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38	CONTINUE	115
GO	T2 6	116
35	CONTINUE	117
END		118
SUBROUTINE	HEADING	119
PRINT	1	120
1	FORMAT(/1X,6HSYMBOL,6Y,3HPPM,5X,9HDET LIMIT,3X,8HCOMMENTS,2X,	121
C4HMASS,3X,3HTLB,4X,2HTB,5Y,4HTSAT,4X,2HTL,4X,3HTLW,8X,1HR,13X,		122
C1HK,9X,2HMF,6X,1HS,8X,2HET/)		123
END		124
SUBROUTINE	CALC K(R,TL,TSAT,EI,AI,KX)	125
TYPE	REAL KX	126
IF	(R.GT.1.25)1+2	127
1	RX1=1.0/1.25	128
GO	TO 5	129
2	IF(R.LJ).1. Q)3+4	130
3	RX1=1.0	131
GO	TO 5	132
4	RX1=1.0/R	133
5	KX=((100.0-TL)/(TL-TSAT))**RX1/(AI*EI)	134
END		135
SUBROUTINE	CALC TLW(R,TLB,TB,TSAT,TLW)	136
IF	(R.GT.1.25)1+2	137
1	TX=1.25	138
RX1=1/1.25		139
GO	TO 3	140
2	RX=R	141
RX1=1.0/R		142
3	TS1=((100.0-TLB)/(TLB-TSAT))**RX1/2.0	143
TS2=((100.0-TB)/(TB-TSAT))**RX1/2.0		144
TS3=(TS1+TS2)**RX		145
TLW=(100.0+TSAT*TS3)/(1.0+TS2)		146
END		147
SUBROUTINE	CALC TL(TLB,TB,TSAT,TL)	148
TS=(100.0-TLB)/(TLB-TSAT)-(100.0-TB)/(TB-TSAT)		149
TL=(100.0+TSAT*TS)/(1.0+TS)		150
END		151
SUBROUTINE	CALC R(TL1,TL2,AE1,AE2,TSAT1,TSAT2,R)	152
R=LOGF((100.0-TL1)/(TL1-TSAT1)*(TL2-TSAT2)/(100.0-TL2))/		153
CLOGF(AE1/AE2)		154
END		155

**Appendix B**  
**SAMPLE PROGRAM OUTPUT**

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## SAMPLE PROGRAM S-50B KERIKCL 8-10-67

SYMBOL	PPM	DET LIMIT	COMMENTS	MASS	TLB	TB	TSAT	TL	TLW	R	K	NP	S	EI	
X	5.000+005	0.0705	REFERENCE	41	56.5	94.6	2.6	58.2	72.1	1.115	3.781+003	1.172	1.00	3.0+003	
				41	27.1	91.2	2.6	27.7	43.1	1.171	3.569+003		1.0+002		
				41	10.5	83.6	2.6	10.6	16.3	1.232	3.775+003		3.0+002		
								RAV=	1.172		4.346+003				
CL	5.042+003	0.0052		35	53.5	97.3	2.6	54.2	70.1	1.120	3.965+001	1.105	1.00	3.0+002	
				35	24.5	96.4	2.6	24.7	39.6	1.120	3.965+001		1.0+001		
								RAV=	1.120	KAV=	4.383+001				
6	1.644+001	0.0148		10	94.6	96.6	2.6	98.1	95.7	1.368	2.321+003	0.542	1.00	1.0+002	
				10	56.5	76.2	2.6	66.2	65.3	1.368	2.994+003		1.0+003		
NA	5.912+001	0.0120		23	78.7	99.3	2.6	79.1	81.6	0.577	9.094+001	0.852	1.00	3.0+001	
				23	65.3	99.3	2.6	65.6	73.6	0.577	5.463+001		1.0+010		
								RAV=	0.577	KAV=	6.008+001				
9	6.084+002	0.0034		11	94.2	96.8	2.6	97.2	95.5	1.550	7.399+004	0.542	1.00	1.0+002	
				11	43.9	77.3	2.6	50.0	56.0	1.550	1.786+003		1.0+013		
								RAV=	1.550	KAV=	9.288+004				
FE	1.169+000	C.0001		56	58.3	81.3	2.6	67.1	68.5	1.372	6.362+003	1.452	1.00	1.0+002	
				56	9.1	35.0	2.6	10.1	14.1	1.372	1.790+003		1.0+003		
								RAV=	1.372	KAV=	1.033+002				
CU	8.097+001	0.0116		63	75.9	90.6	2.6	82.1	83.0	1.273	4.390+003	1.569	1.00	1.0+002	
				63	17.9	47.5	2.6	21.3	26.2	1.273	4.582+003		1.0+003		
								RAV=	1.273	KAV=	7.038+003				
SI	3.328+000	0.1041		29	34.3	72.4	2.6	38.9	47.5	1.659	3.219+002	0.961	1.00	1.0+003	
				30	45.2	70.3	2.6	55.3	55.5	1.659	2.613+002		1.0+003		
								RAV=	1.659	KAV=	2.092+002				
MN	2.925+001	C.0134		55	23.3	35.6	2.6	37.6	28.1	1.000	KAV=	1.768+003	1.438	1.00	1.0+003
								RAV=	1.000	KAV=	2.542+003				
RB	2.166+000	0.0061	F ASSUMED	65	20.5	76.9	2.6	59.1	61.6	1.000	KAV=	1.004+002	1.074	1.00	1.0+002
								RAV=	1.000	KAV=	1.083+002				

**Appendix C**  
**DATA CODING FORM**



**UNCLASSIFIED**

Security Classification

**DOCUMENT CONTROL DATA - R & D**

(Security classification of title, body of abstract and indexing annotation must be entered when the overall report is classified)

1. ORIGINATING ACTIVITY (Corporate author) <b>Naval Research Laboratory Washington, D.C. 20390</b>	2a. REPORT SECURITY CLASSIFICATION <b>Unclassified</b>
	2b. GROUP

## 3. REPORT TITLE

**A COMPUTER PROGRAM FOR THE QUANTITATIVE INTERPRETATION OF MASS SPECTROGRAPHIC PHOTOPLATES**

4. DESCRIPTIVE NOTES (Type of report and inclusive dates) This is a final report on the computer program for determining impurity concentration in solids.

5. AUTHOR(S) (First name, middle initial, last name)

**Paul P. Bey and James G. Allard**

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## 13. ABSTRACT

To determine impurity concentrations in solids using mass spectographs, ion-sensitive emulsions are used. The principal problem in obtaining quantitative results from a mass spectrum recorded on a photographic plate is determining the characteristic response curve. Calculations required to determine the parameters in an empirical function which accurately represents the response curve of Ilford Q2 emulsions are programmed in FORTRAN language. The program input data consists of the impurity-ion mass, line density, and exposure; the impurity-ion concentration and the detection limit are calculated and printed as output.

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